

EAST: [10674612.asymmetrical cells.wsp:1]

FileViewEditToolsWindowHelp

BRS: 32with 33

Pending

Active

Failed

Saved

(1) 09/948877

(1738) "KONINKLUKE PHILIPS". as.

(1) 10/874812

(2481584) memory cell

(0) first adj 10/874812

(54886) first adj (memory cell)

(51108) second adj (memory cell)

(11150) third adj (memory cell)

(120880) symmetries

(120880) symmetry

(976781) symmetry symmetric \$4 mirror

(686846) (asymmetry asymmetric \$4 mirror)

(168889) (asymmetry asymmetric \$4)

(22251) (first adj (memory cell)) near9 (second adj (memory cell))

(84) ((first adj (memory cell)) near9 (second adj (memory cell))) near9 (symmetry symn

(3285) (second adj (memory cell)) near9 (third adj (memory cell))

(3) (((first adj (memory cell)) near9 (second adj (memory cell))) near9 (symmetry symn

(14) ((first adj (memory cell)) near9 (second adj (memory cell)) near9 (symmetry symn

(2) "08274271"

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DBs:USPAT:US PG PUB: EPO: JPO: DERWENT: IBM: TDB

Default operator: OR

Plurals

Highlight all hit terms initially

((first adj (memory cell)) near9 (second adj (memory cell))) near9 (symmetry symmetric \$4 mirror)

) and ((second adj (memory cell)) near9 (third adj (memory cell)))

July 2004

ERS termERS termImageTextHTML

	U	+	inventor	Document#	Issue	P	Title	Current	Current XR	Retrieval	S	C	P	+	+	+	+	Image	Doc	P
1	<input type="checkbox"/>	<input type="checkbox"/>	Nikaido, Hiro	US 6373107	20020	2	Semiconductor storage device having four-lr	257/379/257/903			<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	US 637310	<input type="checkbox"/>	
2	<input type="checkbox"/>	<input type="checkbox"/>	Kasuga, Kenji	US 2004006	20040	2	Semiconductor memory device and method f	365/200			<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	US 200400	<input type="checkbox"/>	
3	<input type="checkbox"/>	<input type="checkbox"/>	Yanagawa, M	US 2004000	20040	1	Associative memory	365/45			<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	US 200400	<input type="checkbox"/>	
4	<input type="checkbox"/>	<input type="checkbox"/>	Yamada, Tos	US 2001002	20011	4	Semiconductor memory	365/210/257/E27.08			<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	US 200100	<input type="checkbox"/>	
5	<input type="checkbox"/>	<input type="checkbox"/>	Ishihara, Kaz	US 2001000	20010	4	Semiconductor failure analysis system	382/148/257/E21.52			<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	US 200100	<input type="checkbox"/>	
6	<input type="checkbox"/>	<input type="checkbox"/>	Ishihara, Kaz	US 6404911	20020	4	Semiconductor failure analysis system	382/149/257/E21.52			<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	US 640491	<input type="checkbox"/>	
7	<input type="checkbox"/>	<input type="checkbox"/>	Yamada, Tos	US 6392953	20020	3	Semiconductor memory	365/230/365/189.12			<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	US 639295	<input type="checkbox"/>	
8	<input type="checkbox"/>	<input type="checkbox"/>	Yamada, Tos	US 6275434	20010	3	Semiconductor memory	365/208/257/E27.08			<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	US 627543	<input type="checkbox"/>	
9	<input type="checkbox"/>	<input type="checkbox"/>	Chih, Yue-Dar	US 6226213	20010	7	Reference cell array to generate the referen	365/210/365/185.01			<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	US 622621	<input type="checkbox"/>	
10	<input type="checkbox"/>	<input type="checkbox"/>	Ishihara, Kaz	US 6185324	20010	4	Semiconductor failure analysis system	382/149/257/E21.52			<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	US 618532	<input type="checkbox"/>	

100

Open

HTML

Ready

3/1/04